

Notice of References Cited	Application/Control No 10/045,659	Applicant(s)/Patent Under Reexamination GOOD ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-3844331	10-1974	Py et al.	164/457
	B	US-3961662	06-1976	Balevski et al.	164/457
	C	US-4585050	04-1986	Merrien et al.	164/457
	D	US-4741381	05-1988	Nishida et al.	164/457
	E	US-5178203	01-1993	Kuhn et al.	164/147.1
*	F	US-5215141	06-1993	Kuhn et al.	164/457
	G	US-5309975	05-1994	Ohnishi et al.	164/66.1
	H	US-5372181	12-1994	Watanabe et al.	164/457
	I	US-5551502	09-1996	Matsubayashi et al.	164/457
	J	US-5597032	01-1997	Merrien	164/457
	K	US-6247521	06-2001	Kawai et al.	164/457
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 0 253 692 A1	01-1988	EPO	Aupetit et al.	B22D 18/08
	O	JP 3-155447	07-1991	Japan	Anami	B22D 18/04
	P	JP 5-96356	04-1993	Japan	Minami et al.	B22D 18/06
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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